

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/848,932	LIEW, JOSEPH SHU YIAN	
Examiner		Art Unit	Page 1 of 1	
David E. Bochna		3679		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,609,734	08-2003	Baugh, Benton F.	285/322
*	B	US-4,902,044	02-1990	Williams et al.	285/18
*	C	US-4,557,508	12-1985	Walker, Stephen J.	285/84
*	D	US-4,191,406	03-1980	Eaton, Edward M.	285/35
*	E	US-3,628,812	12-1971	Larralde et al.	285/24
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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